


<b>Search Notes</b> 	<b>Application/Control No.</b> 10533586	<b>Applicant(s)/Patent Under Reexamination</b> CHONAN ET AL.
	<b>Examiner</b> Tae H Yoon	<b>Art Unit</b> 1796

SEARCHED			
Class	Subclass	Date	Examiner
523	135	6/12/08	/TY/
524	404, 430	6/12/08	/TY/
ATD		6/25/09	/TY/

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, Inventor search	6/12/08	/TY/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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